

Search Notes



Application/Control No.

10/774,656

Examiner

Kin-Chan Chen

Applicant(s)/Patent under Reexamination

DUONG, CHAU H.

Art Unit

1765

SEARCHED

Class	Subclass	Date	Examiner
252	79.1	10/4/05	kcc
	79.3		
252	79.4		
451	41		
451	259		
438	691		
438	693	10/4/05	kcc

INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner

SEARCH NOTES (INCLUDING SEARCH STRATEGY)

	DATE	EXMR
East Keywords search USPAT, USPA - pub. EPO, JPO, Derwent, IBM-TDB. inventor search	10/4/05	kcc